Claims

1. A probe card comprising:

    a wiring board formed with one or more probe electrodes;

    an upper guide plate spaced below the wiring board and facing the wiring board, formed with one or more upper guide holes;

    a lower guide plate spaced below the upper guide plate and facing the upper guide plate, formed with one or more lower guide holes; and

    a probe group including two or more probes that are inserted through a same upper guide hole and a same lower guide hole and connected to a same probe electrode and a same electrode of an object to be inspected; wherein

    the probes of the probe group are capable of independently each other buckling deformation in a predetermined direction between the upper guide plate and the lower guide plate, and their lower ends are capable of moving independently each other in a vertical direction, and

    the two or more probes of the probe group are arranged to be aligned in the predetermined direction.
2. The probe card of claim 1, wherein a friction reduction film is formed on a side surface of the probe.
3. The probe card of claim 1 or 2, wherein the probe includes a locking part that locks onto an upper surface of the upper guide plate to prevent dislodgement from the upper guide plate, and

    the locking part protrudes from a needle base part at an upper part of the probe in a direction perpendicular to the predetermined direction.
4. The probe card of any one of claims 1 to 3, wherein

    a cross-section of an elastic deformation part is rectangular that has a short side in the predetermined direction and a long side perpendicular to the predetermined direction, the elastic deformation part being a part that buckles and deforms in the probe.
5. The probe card of any one of claims 1 to 4, wherein

    the lower guide hole is formed offset to the upper guide hole, and

    the probe in non-inspection is curved between the upper guide plate and the lower guide plate.